

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,163	HASEBE ET AL.	
Examiner	Art Unit	
Truc T. Chuong	2179	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT, USOCR,	,			
USPG_PUB, DERWEN	Tachene	7		
USPG_PUB, DERWEN EPO, JPO, IBM_TAB)	01/08/08	4		
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